

1.0 SCOPE

This specification documents the detail requirements for space qualified die manufactured on Analog Devices, Inc.'s QML certified line per MIL-PRF-38534 class K except as modified herein.

The manufacturing flow described in the STANDARD DIE PRODUCTS PROGRAM brochure at <http://www.analog.com/aerospace> is to be considered a part of this specification.

This data sheet specifically details the space grade version of this product. A more detailed operational description and a complete datasheet for commercial product grades can be found at www.analog.com/OP484

2.0 Part Number. The complete part number(s) of this specification follow:

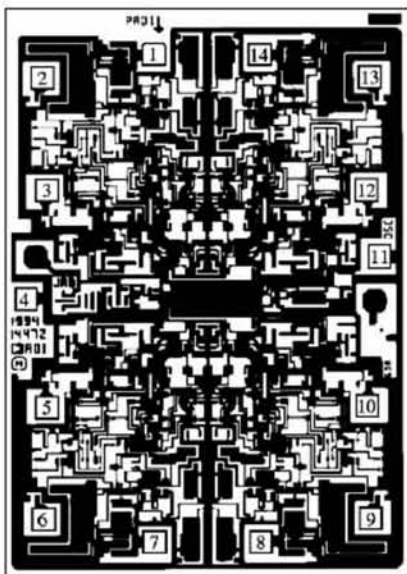
<u>Part Number</u>	<u>Description</u>
OP484-000C	Precision, Rail to Rail Input and Output, Quad Operational Amplifier
OP484R000C	Radiation Tested, Precision, Rail to Rail Input and Output, Quad Operational Amplifier

3.0 Die Information

3.1 Die Dimensions

Die Size	Die Thickness	Bond Pad Metalization
80 mil x 110 mil	19 mil $\pm$ 2 mil	Al/Cu

3.2 Die Picture



1. OUTPUT A
2. -INPUT A
3. +INPUT A
4. +Vs
5. +INPUT B
6. -INPUT B
7. OUTPUT B
8. OUTPUT C
9. -INPUT C
10. +INPUT C
11. -Vs
12. +INPUT D
13. -INPUT D
14. OUTPUT D

3.3 Absolute Maximum Ratings 1/

Supply Voltage	±18V
Differential Input Voltage	±0.6V
Input Voltage	±18V
Output Short Circuit Duration	Indefinite
Storage Temperature Range	-65°C to +150°C
Operating Temperature Range	-55°C to +125°C
Absolute Maximum Ratings Notes:	

- 1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

4.0 Die Qualification

In accordance with class-K version of MIL-PRF-38534, Appendix C, Table C-II, except as modified herein.

(a) Qual Sample Size and Qual Acceptance Criteria – 10/0

(b) Qual Sample Package – DIP

(c) Pre-screen test post assembly required prior to die qualification, to remove all assembly related rejects.

Table I - Dice Electrical Characteristics

Parameter	Symbol	Conditions <u>1/</u>	Limit Min	Limit Max	Units
$V_S = +5V, V_{CM} = 2.5V$					
Input Offset Voltage	V_{OS}			200	μV
Input Offset Current	I_{OS}	<u>2/</u>		50	nA
Input Bias Current	I_B	<u>2/</u>		350	nA
Input Voltage Range	IVR		1	4	V
Common Mode Rejection Ratio	CMRR	$V_{CM} = IVR$	86		dB
Output High Voltage	V_{OH}	$I_L = 1mA$	4.85		V
Output Low Voltage	V_{OL}	$I_L = 1mA$		125	mV
Large Signal Voltage Gain	A_{VO}	$R_L = 2k\Omega,$ $V_{OUT} = 1V \text{ to } 4V$	50		V/mV
Supply Current <u>3/</u>	I_{SY}	$V_{OUT} = 2.5V$		5.8	mA
$V_S = \pm 15V, V_{CM} = 0V$					
Input Offset Voltage	V_{OS}			150	μV
Input Offset Current	I_{OS}			50	nA
Input Bias Current	I_B			350	nA

Table I - Dice Electrical Characteristics (Continued)

Parameter	Symbol	Conditions <u>1/</u>	Limit Min	Limit Max	Units
$V_S = \pm 15V, V_{CM} = 0V$					
Input Voltage Range	IVR		-15	+15	
Common Mode Rejection Ratio	CMRR	$V_{CM} = IVR$	80		dB
Power Supply Rejection Ratio	PSRR	$V_S = \pm 2V$ to $\pm 18V$	90		dB
Large Signal Voltage Gain	A_{VO}	$R_L = 2k\Omega$, $V_{OUT} = \pm 10V$	150		V/mV
Supply Current <u>2/</u>	I_{SY}	$V_{OUT} = 0V$		8	mA

Table I Notes:

1/ $T_A = 25^\circ C$, unless otherwise specified.

2/ Guaranteed by $V_S = \pm 15V$ test.

3/ I_{SY} limit = total all four amplifiers.

Table II - Electrical Characteristics for Qual Samples

Parameter	Symbol	Conditions	Sub-groups	Limit Min	Limit Max	Units	
V _S = +5V, V _{CM} = 2.5V							
Input Offset Voltage	V _{OS}			1		200	μV
				2, 3		400	
		M, D, L, R_3/		1		600	
Input Offset Current	I _{OS}	1/		1, 2, 3		50	nA
		M, D, L, R_3/		1		400	
Input Bias Current	I _B	1/		1		350	
				2, 3		575	
		M, D, L, R_3/		1		3000	
Common Mode Rejection Ratio 4/	CMRR	V _{CM} = 1V to 4V		1, 2, 3	86		dB
Output High Voltage 4/	V _{OH}	I _L = 1mA		4	4.85		V
Output Low Voltage 4/	V _{OL}	I _L = 1mA		4		125	mV
Large Signal Voltage Gain	A _{VO}	R _L = 2kΩ, V _{OUT} = 1V to 4V		4	50		V/mV
				5, 6	25		
		R _L = 10kΩ, V _{OUT} = 1V to 4V	M, D, L, R_3/	4	25		
Supply Current 2/	I _{SY}	V _{OUT} = 2.5V		1		5.8	mA
		M, D, L, R_3/		1		5.85	
V _S = ±15V, V _{CM} = 0V							
Input Offset Voltage 4/	V _{OS}			1		250	μV
				2, 3		500	
Average Input Offset Voltage Drift 4/	TCV _{OS}			8		2	μV/°C
Input Offset Current 4/	I _{OS}			1, 2, 3		50	nA
Input Bias Current 4/	I _B			1		350	nA
				2, 3		575	
Common Mode Rejection Ratio 4/	CMRR	V _{CM} = -15V to +15V		1, 2, 3	80		dB
Power Supply Rejection Ratio 4/	PSRR	V _S = ±2V to ±18V		1, 2, 3	90		dB
Large Signal Voltage Gain 4/	A _{VO}	R _L = 2kΩ, V _{OUT} = ±10V		4	150		V/mV
				5, 6	75		
Supply Current 2/ 4/	I _{SY}	V _{OUT} = 0V		1		8	mA
		V _S = ±18V, V _{OUT} = 0V		1, 2, 3		9	

Table II Notes:

- 1/ Guaranteed by $V_S = \pm 15V$ test.
- 2/ I_{SY} limit = total all four amplifiers.
- 3/ Devices tested at 100Krad irradiation.
- 4/ Parameter not tested post irradiation.

Table III - Life Test Endpoint and Delta Parameter (Product is tested in accordance with Table II with the following exceptions)								
Parameter	Symbol	Sub-groups	Burn In Limit Min	Burn In Limit Max	Life Test Limit Min	Life Test Limit Max	Life Test Delta	Units
Input Offset Voltage $V_S = \pm 15V$	V_{OS}	1		500		750	± 250	μV
		2, 3				1000		
Input Bias Current $V_S = \pm 15V$	I_B	1		450		550	± 100	nA
		2, 3				775		
Input Offset Current $V_S = \pm 15V$	I_{OS}	1		60		100	± 40	nA
		2, 3				100		
Input Offset Voltage $V_S = +5V$	V_{OS}	1		300		450		μV
		2, 3				650		

5.0 Life Test/Burn-In Information

- 5.1** HTRB is not applicable for this drawing.
- 5.2** Burn-in is per MIL-STD-883 Method 1015 test condition B or C.
- 5.3** Steady state life test is per MIL-STD-883 Method 1005.

OP484 Quad Precision, Rail to Rail Input and
Output, Quad Operational Amplifier

Rev	Description of Change	Date
A	Initiate	25-Sep-07
B	Update web address	Jan. 25, 2002
C	Add radiation part number. Update web address	Feb. 10, 2003